Seal	rcn No	otes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/820,122	WU ET AL.
Examiner	Art Unit
David Buttner	1712

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEA (INCLUDING	ARCH NOTES SEARCH STRATEGY	·)
	DATE	EXMR
chem ab	8/23/2005	DB
east	8/23/2005	DB
west	8/25/2005	DB
chem ab	8/25/2005	DB